PATENT COOPERATION TREATY



PCT

INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

(Chapter II of the Patent Cooperation Treaty)

(PCT Article 36 and Rule 70)

(0 1 1 2 3 1					
Applicant's or agent's file reference 10701-GE-PCT	FOR FURTHER A	CTION	See Form PCT/IPEA/416		
International application No. PCT/JP2003/016012	International filing da 15 December 20	te (day/month/year) 003 (15.12.2003)	Priority date (day/month/year) 20 October 2003 (20.10.2003)		
International Patent Classification (IPC) or n H01L 25/065, 25/07, 25/18	International Patent Classification (IPC) or national classification and IPC				
Applicant	GENUSI	ON INC.			
This report is the international prelin Authority under Article 35 and trans	ninary examination rep mitted to the applicant	ort, established by this according to Article 36	International Preliminary Examining 5.		
2. This REPORT consists of a total of		•	heet.		
3. This report is also accompanied by A	ANNEXES, comprising	:			
a. (sent to the applicant and	to the International Bu	reau) a total of <u>6</u>	sheets, as follows:		
sheets of the descr and/or sheets cont Administrative Ins	aining rectifications au	rawings which have be thorized by this Autho	een amended and are the basis of this report rity (see Rule 70.16 and Section 607 of the		
sheets which supe beyond the disclo Supplemental Box	sure in the internationa	t which this Authority I application as filed,	considers contain an amendment that goes as indicated in item 4 of Box No. I and the		
		total of (indicate tvi	pe and number of electronic carrier(s))		
	, contai dicated in the Supplen	ning a sequence listing	g and/or tables related thereto, in computer Sequence Listing (see Section 802 of the		
4. This report contains indications relat	ing to the following ite	ms:			
Box No. I Basis of the re	port				
Box No. II Priority					
Box No. III Non-establishr	nent of opinion. with re	gard to novelty, invent	ive step and industrial applicability		
Box No. IV Lack of unity of	of invention				
Box No. V Reasoned statement under Article 35(2) with regard to noveity, inventive step or industrial applicabilications and explanations supporting such statement			ity, inventive step or industrial applicability;		
Box No. VI Certain documents cited					
Box No. VII Certain defects in the international application					
Box No. VIII Certain observations on the international application					
Date of submission of the demand		Date of completion o	f this report		
19 May 2005 (19.05.20	005)	27 0	ctober 2005 (27.10.2005)		
Name and mailing address of the IPEA/JP		Authorized officer			
Facsimile No.		Telephone No.			

Translation

International application No.

PCT/JP2003/016012

INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

Box No.	. I I	Basis of the report				
1. With other	regard	to the language, this report is bardicated under this item.	sed on the international application in the lang	guage in which it was filed, unless		
	This report is based on translations from the original language into the following language, which is language of a translation furnished for the purpose of:					
	international search (under Rules 12.3 and 23.1(b))					
		publication of the international a	pplication (under Rule 12.4)			
			ation (under Rules 55,2 and/or 55,3)			
			ŕ			
furni	shed to are not c	to the elements of the interna the receiving Office in response annexed to this report): ternational application as origina	tional application, this report is based on to an invitation under Article 14 are referre . !!y filed/furnished	(replacement sheets which have been d to in this report as "originally filed"		
	the des	scription:				
	pages		5-15	, as originally filed/furnished		
	pages*	1-4	received by this Authority on	07 October 2005 (07.10.2005)		
	pages*		received by this Authority on			
	the cla	ims:				
	pages			, as originally filed/furnished		
j	pages*		, as amended (tog	ether with any statement) under Article 19		
	pages*	1,7,8,10-12	received by this Authority on	07 October 2005 (07.10.2005)		
1	pages*		received by this Authority on			
	the dra	wings:				
	pages		1-9	, as originally filed/furnished		
	pages*		received by this Authority on	, as originary modifications		
	pages*		received by this Authority on			
	a segu	ence listing and/or any related tal	ole(s) – see Supplemental Box-Relating to Sec	Quence Listing		
''		and or any related tal	socio, socioappionental Box Rolating to box	quence Disting.		
3.	The an	nendments have resulted in the ca	ancellation of:			
		the description, pages				
		the claims, Nos	2-6,9			
		the drawings, sheets/figs				
·	any table(s) related to sequence listing (specify):					
	_		3(1-3)/-			
4. 🗌	made, (Rule 1	since they have been considere 70.2(c)). the description, pages	(some of) the amendments annexed to this red to go beyond the disclosure as filed, as			
i	Ħ.	he drawings sheets/fice				
	=	=				
	LJ ⁸	any table(s) related to sequence li	isting (specify):			
* If iten	n 4 appi	lies, some or all of those sheets m	nay be marked "superseded."			

INTERNATIONAL PRELIMINARY EXAMINATION REPORT

International application No. PCT/JP 03/16012

V.	Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability;
	citations and explanations supporting such statement

1. Statement			
Novelty (N)	Claims	8, 10, 11	YES
	Claims	1, 7	NO
Inventive step (IS)	Claims		YES
	Claims	1, 7, 8, 10, 11	NO NO
Industrial applicability (IA)	Claims	1, 7, 8, 10, 11	YES
	Claims		NO

Citations and explanations

- Document 1: JP 5-343608 A (Hitachi, Ltd.), 24 December 1993
- Document 2: JP 10-335574 A (Nippon Telegraph And Telephone Corp.), 18 December 1998
- Document 3: JP 62-134939 A (Sony Corp.), 18 June 1987
- Document 4: JP 2-139669 A (Mitsubishi Mining and Cement Co., Ltd.), 29 May 1990
- Document 5: JP 11-204719 A (Toshiba Corp.), 30 July 1999, column 9, lines 9 to 39 and fig. 7 (Family: none)
- Document 6: JP 8-236693 A (NEC Corp.), 13 September 1996, column 1, lines 27 to 33 (Family: none)
- Document 7: JP 8-70024 A (Fujitsu Ltd.), 12 March 1996, column 7, lines 7 to 23 and fig. 1 and 4 (Family: none)
- Document 8: JP 9-330961 A (Hitachi, Ltd.), 22 December
 1997, column 4, line 23 to column 5, line 19
 and fig. 1 to 3 (Family: none)

The inventions set forth in claims 1 and 7 lack novelty in the light of newly cited document 5. Document 5 discloses a semiconductor device wherein an intermediate mounting substrate (9), which comprises wires and memory

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chips that have been sealed by means of a resin (37), is mounted and connected to a semiconductor chip (1), the semiconductor chip (1) is then mounted upon a mounting substrate and the resulting structure is sealed by means of a resin (38). Therein, there is no difference between the semiconductor device that is disclosed in document 5 and the semiconductor device that comprises a subsubstrate for mounting a semiconductor chip wherein the test terminals have been cut away.

The inventions set forth in claims 1 and 7 lack novelty in the light of document 1 cited in the international search report. Document 1 discloses a hybrid integrated circuit device that is configured by forming a sub-assembly (2) with a chip resistor (12) and an integrated circuit (13) mounted thereupon, which is covered with a package (15) that was formed by means of a transfer mold; mounting the aforementioned sub-assembly (2), the chip resistor (3) and the integrated circuit (4) upon a wiring substrate (1); and then covering the resulting structure with a package (8) that was formed by means of a transfer mold. Therein, there is no difference between the semiconductor device that is disclosed in document 1 and the semiconductor device that comprises a sub-substrate for mounting a semiconductor chip wherein the test terminals have been cut away.

The inventions set forth in claims 8, 10 and 11 do not involve an inventive step-in the light of document 1 cited in the international search report and newly cited documents 5 to 8. Document 6 discloses a multi-chip module that is configured by mounting a plurality of chips upon a sub-substrate in advance, inspecting the resulting structure and thereafter mounting the resulting structure upon a single substrate. In addition, documents 7 and 8 disclose semiconductor devices wherein inspection pads are provided to the peripheral parts of the substrate, and are

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	then	cut	away	and	removed	after	inspection.
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